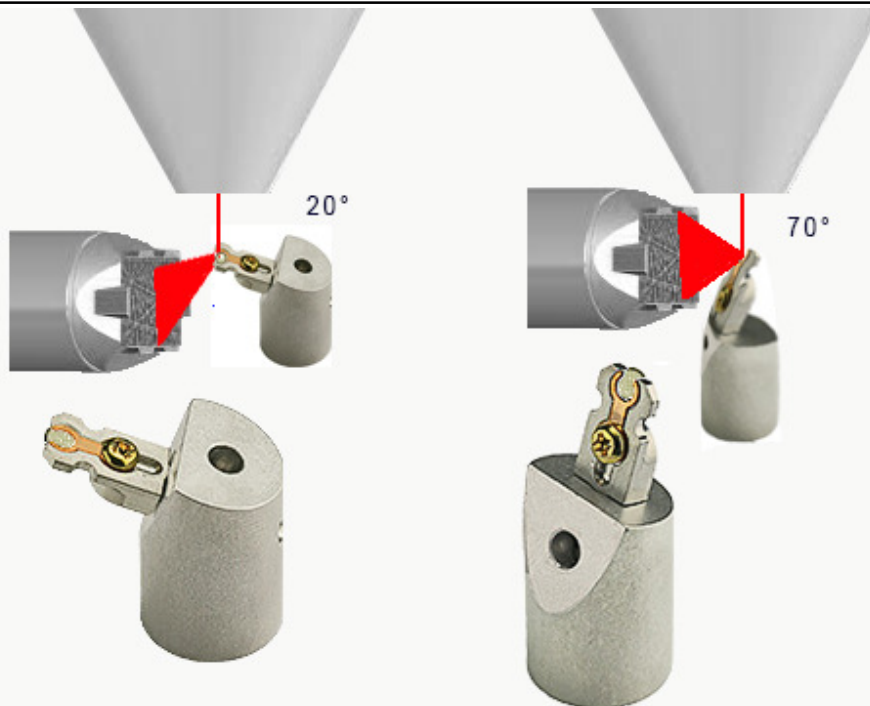


EBSA analysis is a powerful microstructural crystallographic characterisation technique for crystalline or polycrystalline materials. Standard EBSA analysis on bulk samples and surfaces is performed on high-tilt samples (typically 70° from horizontal). The EBSA pattern reveals the crystal orientation and in polycrystalline materials the variation of orientation amongst the crystals. For optimum EBSA results, deformation free, polished surfaces are needed.

Transmission EBSA analysis is only possible on (very) thin TEM samples suspended on a TEM grid or on a TEM lamella attached to an FIB grid. EBSA analysis on thin samples can be performed in backscatter mode at 70° tilt (from horizontal) or transmission mode at 20° (from horizontal). For transmission EBSA or t-EBSA it is imperative that transmitted electrons can reach the EBSA detector without any obstruction.

Our t-EBSA holders are specifically designed to generate transmission Kikuchi patterns. The transmission EBSA holders include an opening of 2mm Ø in the base. The top is formed by a fork-shaped phosphor-bronze clip which clamps the TEM or FIB grid. Transmission EBSA imaging and analysis is possible over the 2mm Ø area.

EBSA Sample Holders for TEM & FIB Grids



The t-EBSA holders are available with 1 or 3 TEM grid capacity.



S738 t-EBSA holder for three (3) TEM/FIB lift-out grids [standard pin](#)

S739 t-EBSA holder for one (1) TEM/FIB lift-out grid [standard pin](#)

S740 3x replacement t-EBSA TEM grid clips plus 3x M2 3mm brass screws

S741 t-EBSA holder kit 20°/70° for three TEM/FIB lift-out grids [standard pin](#)

S742 t-EBSA holder kit 20°/70° for single TEM/FIB lift-out grid [standard pin](#)

S743 t-EBSA holder kit 20°/70° for three TEM/FIB lift-out grids [M4](#)

S744 t-EBSA holder kit 20°/70° for single TEM/FIB lift-out grid [M4](#)

Note

The EBSA sample holder kits combine a number of available SEM holders: metallographic mount holders or geological slide holders with the EBSA 70° pre-tilt holder and a height extender for the 30mm/1¼" EBSA sample holder to provide clearance. The height extender can be easily removed if the stage adapter on the SEM stage does not require it. The EBSA 70° pre-tilt holders are available with either a pin or M4 threaded hole.

Using a stub adapter for JEOL SEMs is only advised if there is enough height clearance or if the JEOL SEM has been converted to use pin stubs.

EBSD Pre-Tilt Sample Holders & Kits

The EBSD pre-tilt sample holders all include a 70° pre-tilt angle to facilitate EBSD analysis. With a 70° pre-tilt angle there is no need to tilt the SEM sample stage. Using pre-tilted holders instead of tilting the SEM stage offers the following advantages:

- Correct EBSD angle when loading sample
- No stage drift in Z-direction
- Choice of 70° or 20° pre-tilt

The EBSD sample holder kits combine a number of available SEM sample holders: metallographic mount holders, geological slide holder, small vice type holders and S-Clip holders. These are combined with the EBSD 70° pre-tilt holder and a height extender if needed. The P70 and H70 pre-tilt EBSD holders include both 70° pre-tilt and -20° pre-tilt to enable EBSD measurements at a 90° angle on the same sample. The EBSD 70° pre-tilt holders are available with pin and M4 threaded hole.

- S745** P70 EBSD 70° pre-tilt holder for pin stubs/holders, 12.7mm Ø x 20mm, on [pin base](#)
- S746** P70M EBSD 70° pre-tilt holder for Hitachi M4 stubs/holders, 12.7mm Ø x 20mm, on [pin](#)
- S747** H70P EBSD 70° pre-tilt holder for pin stubs/holders, 12.7mm Ø x 20mm, [M4 base](#)
- S748** H70 EBSD 70° pre-tilt holder for Hitachi M4 stubs/holders, 12.7mm Ø x 20mm, [M4 base](#)

- S749** P71 EBSD 70° pre-tilt sample holder for 25mm Ø/1" Ø mounts, on [pin base](#)
- S750** P72 EBSD 70° pre-tilt sample holder for 30mm /32mm/1¼" Ø mounts, on [pin base](#)
- S751** H71 EBSD 70° pre-tilt sample holder for 25mm Ø/1" Ø mounts, [M4 base](#)
- S752** H72 EBSD 70° pre-tilt sample holder 30mm /32mm/1¼" Ø mounts, [M4 base](#)

- S753** P78 EBSD 70° pre-tilt vice clamp holder for samples up to 16mm, on [pin base](#)
- S754** P77 EBSD 70° pre-tilt vice clamp holder for cross sections up to 8mm, on [pin base](#)
- S755** P76 EBSD 70° pre-tilt mini-vice holder for sample cross sections up to 4mm, [pin base](#)
- S756** H78 EBSD 70° pre-tilt vice clamp holder for samples up to 16mm, [M4 base](#)
- S757** H77 EBSD 70° pre-tilt vice clamp holder for cross sections up to 8mm, [M4 base](#)
- S758** H76 EBSD 70° pre-tilt mini-vice holder for sample cross sections up to 4mm, [M4 base](#)

- S759** P75 EBSD 70° pre-tilt S-Clip sample holder for Si-chips/thin samples, on [pin base](#)
- S760** H75 EBSD 70° pre-tilt S-Clip sample holder for Si-chips/thin samples, [M4 base](#)

- S761** P74 EBSD 70° pre-tilt sample holder for FIB lift-out lamella, on [pin base](#)
- S762** H74 EBSD 70° pre-tilt sample holder for FIB lift-out lamella, [M4 base](#)

- S763** P73 EBSD 70° pre-tilt sample holder for geological slides up to 48 x 28mm, [pin base](#)
- S764** H73 EBSD 70° pre-tilt sample holder for geological slides up to 48 x 28mm, [M4 base](#)

